Self-Protected Low Side Driver with Temperature and Current Limit

NCV8402, NCV8402A

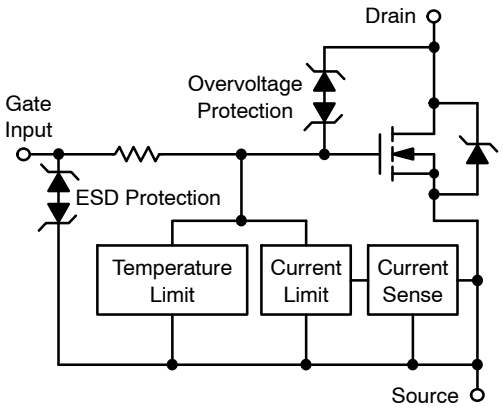
NCV8402/A is a three terminal protected Low−Side Smart Discrete device. The protection features include overcurrent, overtemperature, ESD and integrated Drain−to−Gate clamping for overvoltage protection. This device offers protection and is suitable for harsh automotive environments.

Features

- Short−Circuit Protection
- Thermal Shutdown with Automatic Restart
- Overvoltage Protection
- Integrated Clamp for Inductive Switching
- ESD Protection
- NCV8402AMNWT1G − Wettable Flanks Product
- dV/dt Robustness
- Analog Drive Capability (Logic Level Input)
- NCV Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC−Q101 Qualified and PPAP Capable
- These Devices are Pb−Free and are RoHS Compliant

Typical Applications

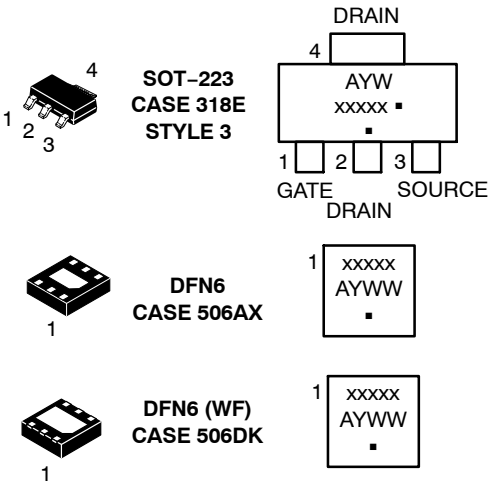
- Switch a Variety of Resistive, Inductive and Capacitive Loads
- Can Replace Electromechanical Relays and Discrete Circuits
- Automotive / Industrial



$V_{(BR)DSS}$ (Clamped)	$R_{DS(ON)}$ TYP	I_D MAX
42 V	165 mΩ @ 10 V	2.0 A*

*Max current limit value is dependent on input condition.

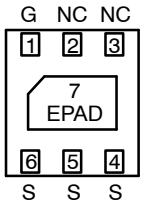
MARKING DIAGRAMS



A = Assembly Location
Y = Year
W or WW = Work Week
xxxxx = V8402 or 8402A
▪ = Pb−Free Package

(Note: Microdot may be in either location)

DFN6 PACKAGE PIN DESCRIPTION



Pin #	Symbol	Description
1	G	Gate Input
2	NC	No Connect
3	NC	No Connect
4	S*	Source
5	S*	Source
6	S*	Source
7	EPAD	Drain

*Pins 4, 5, 6 are internally shorted together.
It is recommended to short these pins externally.

ORDERING INFORMATION

See detailed ordering and shipping information on page 11 of this data sheet.

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Rating		Symbol	Value	Unit
Drain−to−Source Voltage Internally Clamped		V_{DSS}	42	V
Drain−to−Gate Voltage Internally Clamped	(R_G = 1.0 MΩ)	V_{DGR}	42	V
Gate−to−Source Voltage		V_{GS}	±14	V
Continuous Drain Current		I_D	Internally Limited	
Total Power Dissipation − SOT−223 Version	@ T_A = 25°C (Note 1) @ T_A = 25°C (Note 2) @ T_S = 25°C)	P_D	1.1 1.74 8.9	W
Total Power Dissipation − DFN Version	@ T_A = 25°C (Note 1) @ T_A = 25°C (Note 2) @ T_S = 25°C)	P_D	0.76 1.78 8.9	W
Maximum Continuous Drain Current − SOT−223 Version	@ T_A = 25°C (Note 1) @ T_A = 25°C (Note 2) @ T_S = 25°C)	I_D	1.54 1.94 6.75	A
Maximum Continuous Drain Current − DFN Version	@ T_A = 25°C (Note 1) @ T_A = 25°C (Note 2) @ T_S = 25°C)	I_D	1.28 1.97 6.75	A
Thermal Resistance	SOT223 Junction−to−Ambient Steady State (Note 1) SOT223 Junction−to−Ambient Steady State (Note 2) SOT223 Junction−to−Soldering Point Steady State DFN Junction−to−Ambient Steady State (Note 1) DFN Junction−to−Ambient Steady State (Note 2) DFN Junction−to−Soldering Point Steady State	$R_{\theta JA}$ $R_{\theta JA}$ $R_{\theta JS}$ $R_{\theta JA}$ $R_{\theta JA}$ $R_{\theta JS}$	114 72 14 163 70 14	°C/W
Single Pulse Drain−to−Source Avalanche Energy (V_{DD} = 32 V, V_G = 5.0 V, I_{PK} = 1.0 A, L = 300 mH, $R_{G(ext)}$ = 25 Ω)		E_{AS}	150	mJ
Load Dump Voltage	(V_{GS} = 0 and 10 V, R_I = 2.0 Ω, R_L = 9.0 Ω, t_d = 400 ms)	V_{LD}	55	V
Operating Junction Temperature		T_J	−40 to 150	°C
Storage Temperature		T_{stg}	−55 to 150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Surface−mounted onto min pad FR4 PCB, (2 oz. Cu, 0.06″ thick).
2. Surface−mounted onto 2″ sq. FR4 board (1″ sq., 1 oz. Cu, 0.06″ thick).

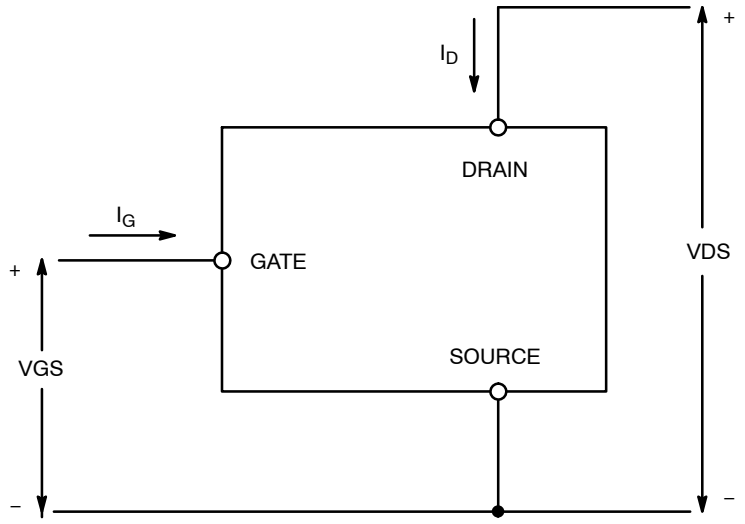


Figure 1. Voltage and Current Convention

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

Parameter	Test Condition	Symbol	Min	Typ	Max	Unit
OFF CHARACTERISTICS						
Drain−to−Source Breakdown Voltage (Note 3)	V_{GS} = 0 V, I_D = 10 mA, T_J = 25°C	$V_{(BR)DSS}$	42	46	55	V
	V_{GS} = 0 V, I_D = 10 mA, T_J = 150°C (Note 5)		40	45	55	
Zero Gate Voltage Drain Current	V_{GS} = 0 V, V_{DS} = 32 V, T_J = 25°C	I_{DSS}		0.25	4.0	μA
Zero Gate Voltage Drain Current	V_{GS} = 0 V, V_{DS} = 32 V, T_J = 150°C (Note 5)	I_{DSS}		1.1	20	μA
Gate Input Current	V_{DS} = 0 V, V_{GS} = 5.0 V	I_{GSSF}		50	100	μA
ON CHARACTERISTICS (Note 3)						
Gate Threshold Voltage	V_{GS} = V_{DS}, I_D = 150 μA	$V_{GS(th)}$	1.3	1.8	2.2	V
Gate Threshold Temperature Coefficient		$V_{GS(th)}/T_J$		4.0		−mV/°C
Static Drain−to−Source On−Resistance	V_{GS} = 10 V, I_D = 1.7 A, T_J = 25°C	$R_{DS(on)}$		165	200	mΩ
	V_{GS} = 10 V, I_D = 1.7 A, T_J = 150°C (Note 5)			305	400	
	V_{GS} = 5.0 V, I_D = 1.7 A, T_J = 25°C			195	230	
	V_{GS} = 5.0 V, I_D = 1.7 A, T_J = 150°C (Note 5)			360	460	
	V_{GS} = 5.0 V, I_D = 0.5 A, T_J = 25°C			190	230	
	V_{GS} = 5.0 V, I_D = 0.5 A, T_J = 150°C (Note 5)			350	460	
Source−Drain Forward On Voltage	V_{GS} = 0 V, I_S = 7.0 A	V_{SD}		1.0		V
SWITCHING CHARACTERISTICS (Note 5)						
Turn−On Time (10% V_{IN} to 90% I_D)	V_{GS} = 10 V, V_{DD} = 12 V, I_D = 2.5 A, R_L = 4.7 Ω	t_{on}		25	30	μs
Turn−Off Time (90% V_{IN} to 10% I_D)		t_{off}		120	200	μs
Turn−On Rise Time (10% I_D to 90% I_D)		t_{rise}		20	25	μs
Turn−Off Fall Time (90% I_D to 10% I_D)		t_{fall}		50	70	μs
Slew−Rate ON (70% to 50% V_{DD})		$-dV_{DS}/dt_{ON}$		0.8	1.2	V/μs
Slew−Rate OFF (50% to 70% V_{DD})		dV_{DS}/dt_{OFF}		0.3	0.5	V/μs
SELF PROTECTION CHARACTERISTICS (T_J = 25°C unless otherwise noted) (Note 4)						
Current Limit	V_{DS} = 10 V, V_{GS} = 5.0 V, T_J = 25°C (Note 6)	I_{LIM}	3.7	4.3	5.0	A
	V_{DS} = 10 V, V_{GS} = 5.0 V, T_J = 150°C (Notes 5, 6)		2.3	3.0	3.7	
	V_{DS} = 10 V, V_{GS} = 10 V, T_J = 25°C (Note 6)		4.2	4.8	5.4	
	V_{DS} = 10 V, V_{GS} = 10 V, T_J = 150°C (Notes 5, 6)		2.7	3.6	4.5	
Temperature Limit (Turn−off)	V_{GS} = 5.0 V (Notes 5, 6)	$T_{LIM(off)}$	150	175	200	°C
Thermal Hysteresis	V_{GS} = 5.0 V	$\Delta T_{LIM(on)}$		15		
Temperature Limit (Turn−off)	V_{GS} = 10 V (Notes 5, 6)	$T_{LIM(off)}$	150	165	185	
Thermal Hysteresis	V_{GS} = 10 V	$\Delta T_{LIM(on)}$		15		
GATE INPUT CHARACTERISTICS (Note 5)						
Device ON Gate Input Current	V_{GS} = 5 V I_D = 1.0 A	I_{GON}		50		μA
	V_{GS} = 10 V I_D = 1.0 A			400		

3. Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
4. Fault conditions are viewed as beyond the normal operating range of the part.
5. Not subject to production testing.
6. Refer to Application Note AND8202/D for dependence of protection features on gate voltage.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

Parameter	Test Condition	Symbol	Min	Typ	Max	Unit
GATE INPUT CHARACTERISTICS (Note 5)						
Current Limit Gate Input Current	V_{GS} = 5 V, V_{DS} = 10 V	I_{GCL}		0.05		mA
	V_{GS} = 10 V, V_{DS} = 10 V			0.4		
Thermal Limit Fault Gate Input Current	V_{GS} = 5 V, V_{DS} = 10 V	I_{GTL}		0.15		mA
	V_{GS} = 10 V, V_{DS} = 10 V			0.7		
ESD ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted) (Note 5)						
Electro−Static Discharge Capability	Human Body Model (HBM)	ESD	4000			V
	Machine Model (MM)		400			

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

3. Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
4. Fault conditions are viewed as beyond the normal operating range of the part.
5. Not subject to production testing.
6. Refer to Application Note AND8202/D for dependence of protection features on gate voltage.

TYPICAL PERFORMANCE CURVES

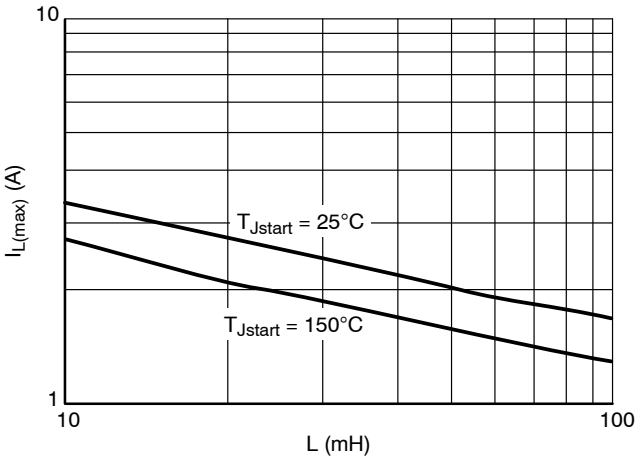


Figure 2. Single Pulse Maximum Switch−off Current vs. Load Inductance

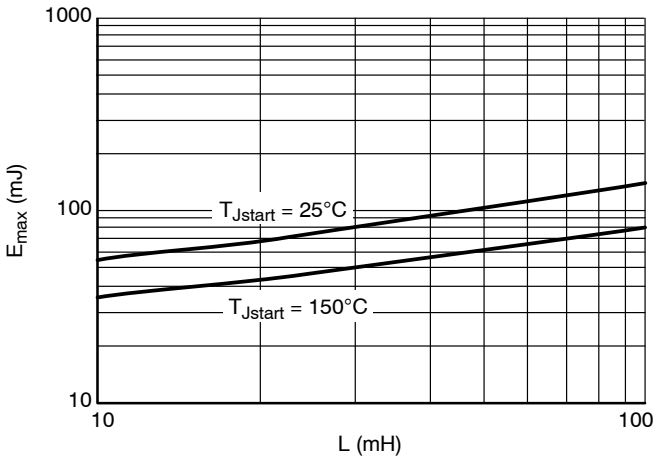


Figure 3. Single Pulse Maximum Switching Energy vs. Load Inductance

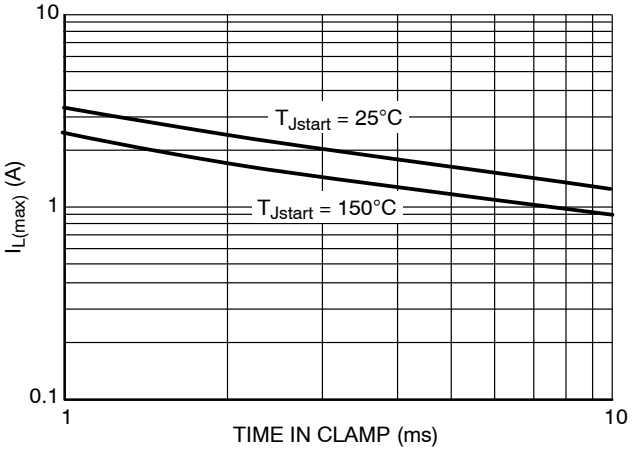


Figure 4. Single Pulse Maximum Inductive Switch−off Current vs. Time in Clamp

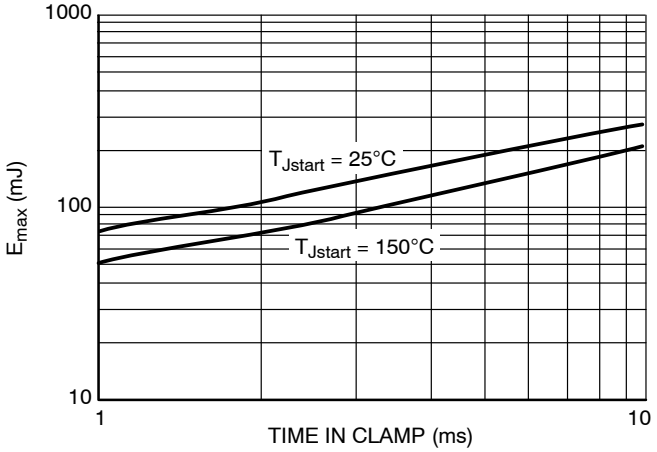


Figure 5. Single Pulse Maximum Inductive Switching Energy vs. Time in Clamp

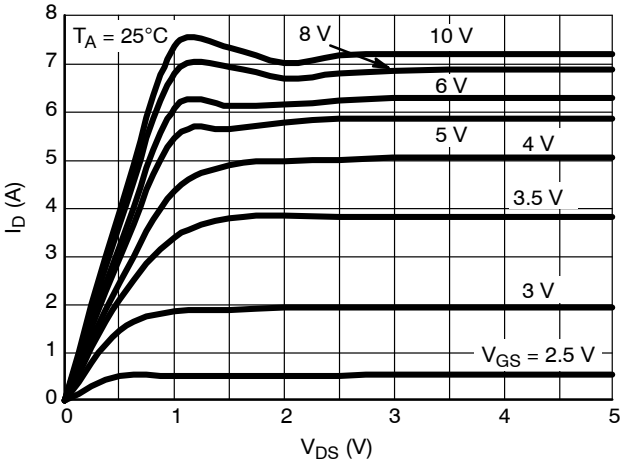


Figure 6. On−state Output Characteristics

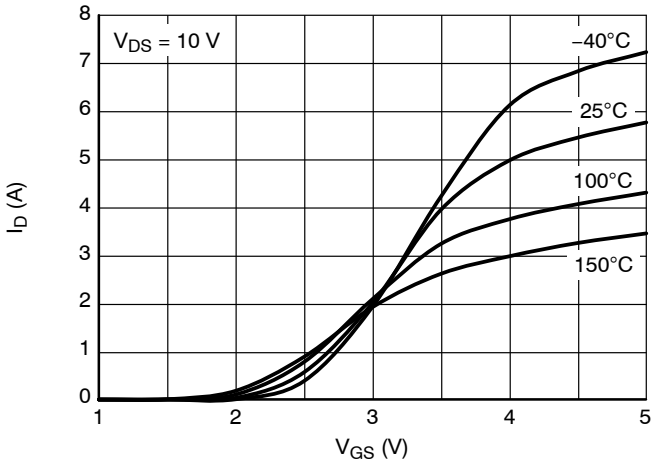


Figure 7. Transfer Characteristics

TYPICAL PERFORMANCE CURVES

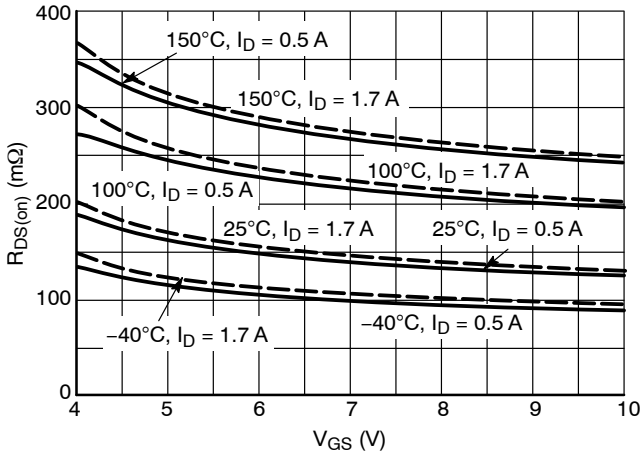


Figure 8. $R_{DS(on)}$ vs. Gate−Source Voltage

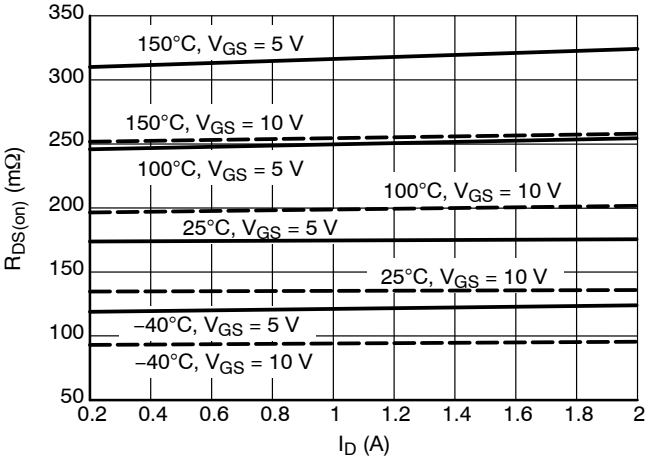


Figure 9. $R_{DS(on)}$ vs. Drain Current

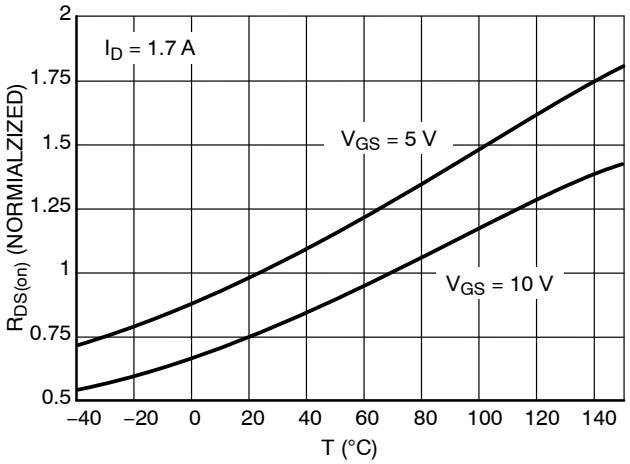


Figure 10. Normalized $R_{DS(on)}$ vs. Temperature

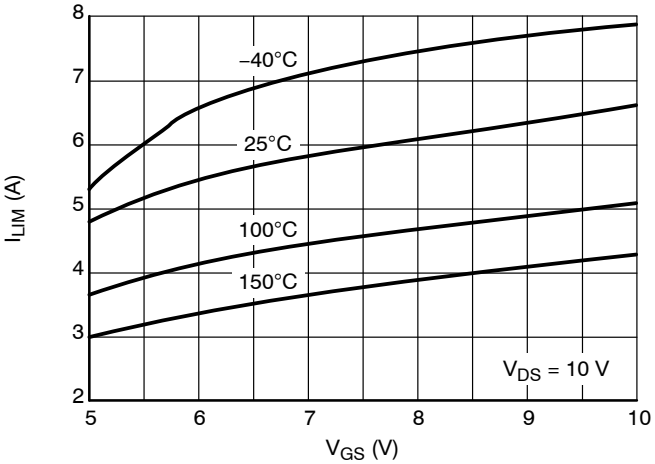


Figure 11. Current Limit vs. Gate−Source Voltage

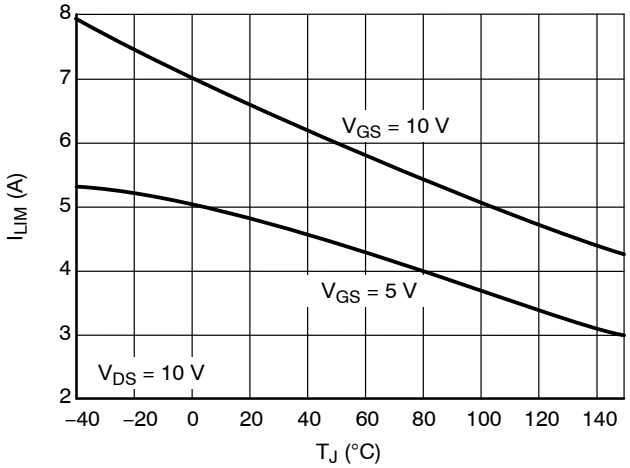


Figure 12. Current Limit vs. Junction Temperature

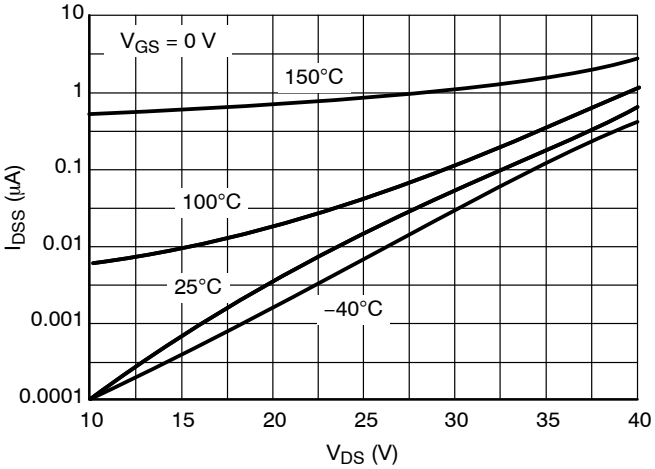


Figure 13. Drain−to−Source Leakage Current

TYPICAL PERFORMANCE CURVES

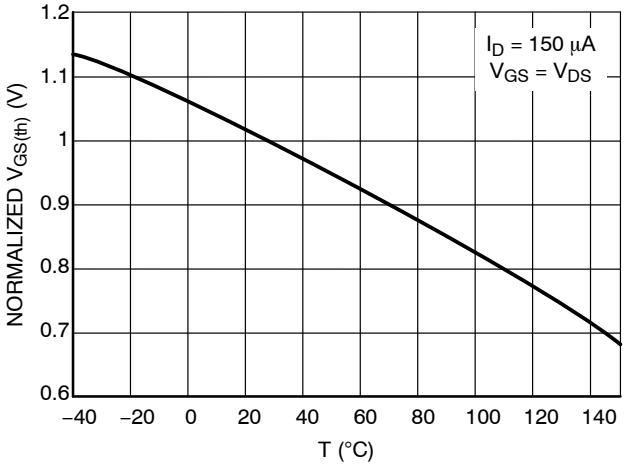


Figure 14. Normalized Threshold Voltage vs. Temperature

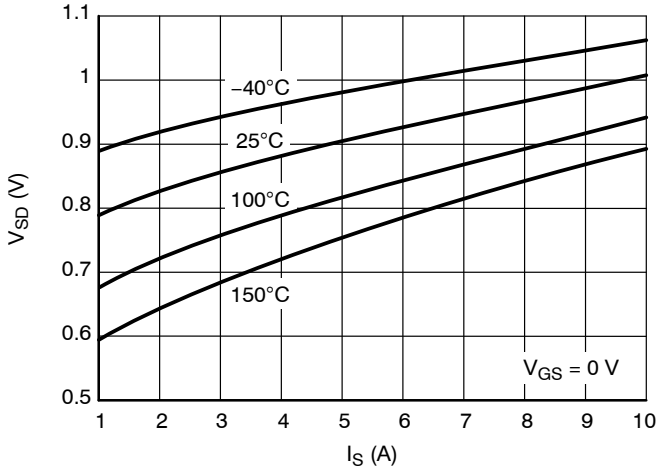


Figure 15. Source−Drain Diode Forward Characteristics

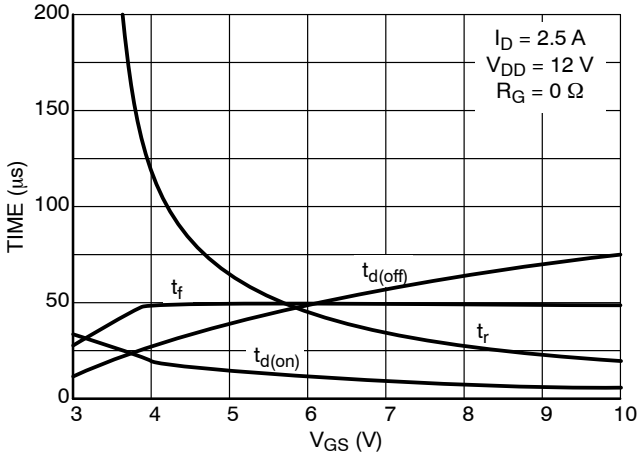


Figure 16. Resistive Load Switching Time vs. Gate−Source Voltage

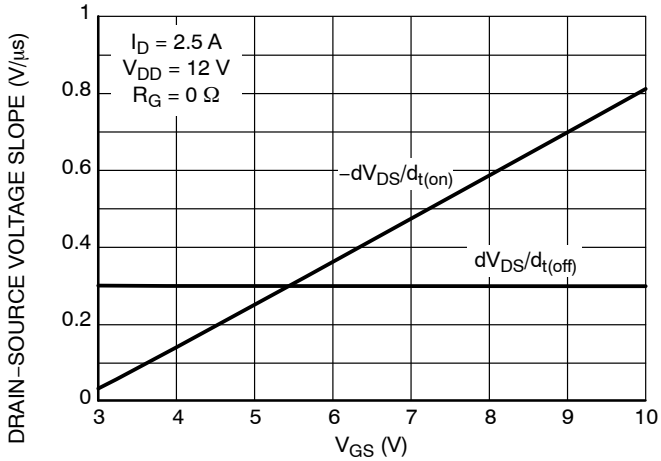


Figure 17. Resistive Load Switching Drain−Source Voltage Slope vs. Gate−Source Voltage

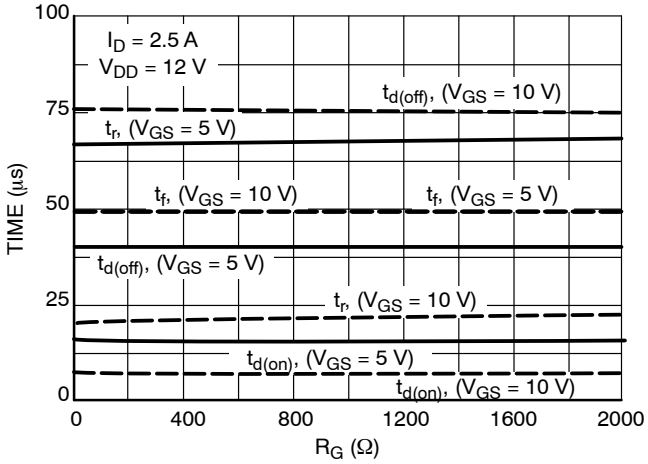


Figure 18. Resistive Load Switching Time vs. Gate Resistance

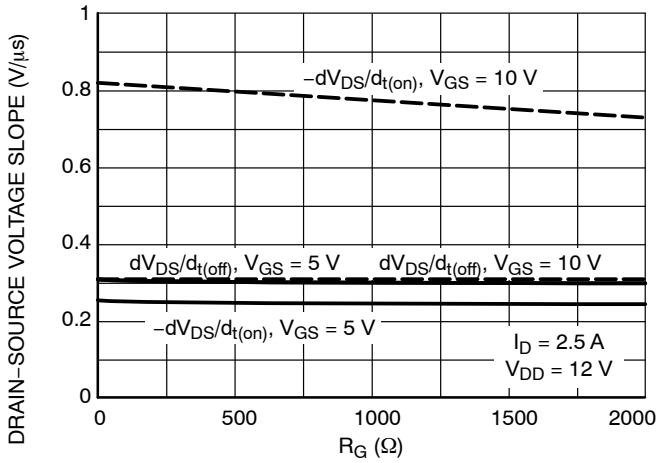


Figure 19. Drain−Source Voltage Slope during Turn On and Turn Off vs. Gate Resistance

TYPICAL PERFORMANCE CURVES

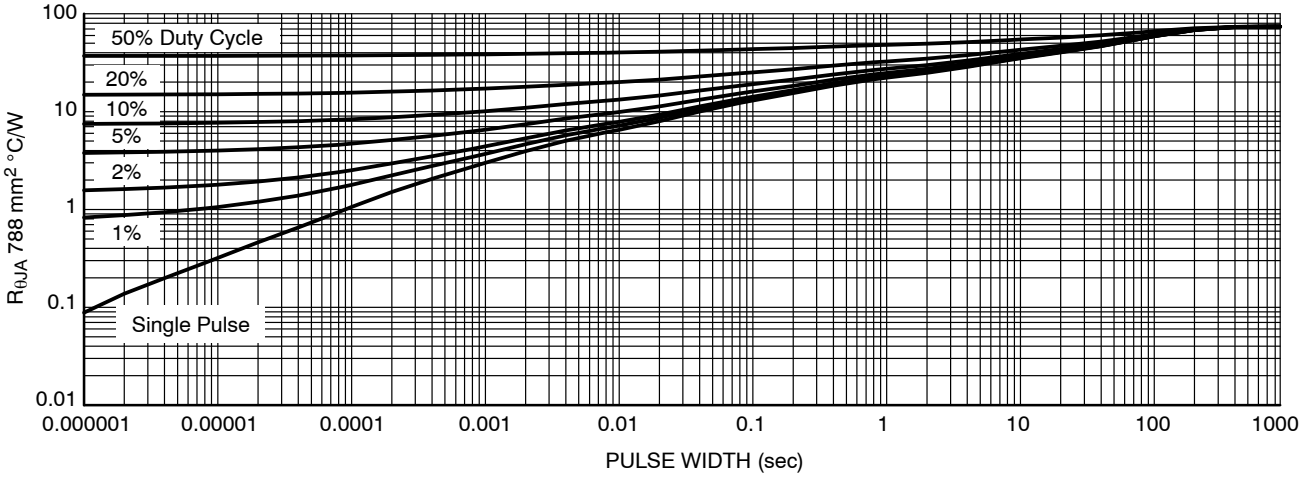


Figure 20. Transient Thermal Resistance – SOT−223 Package

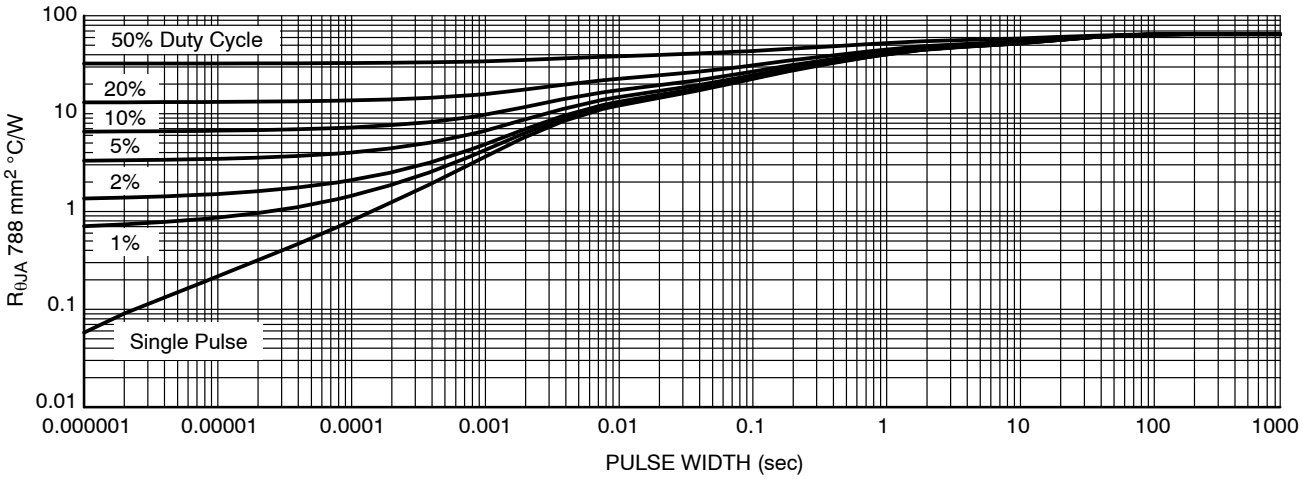


Figure 21. Transient Thermal Resistance – DFN Package

TEST CIRCUITS AND WAVEFORMS

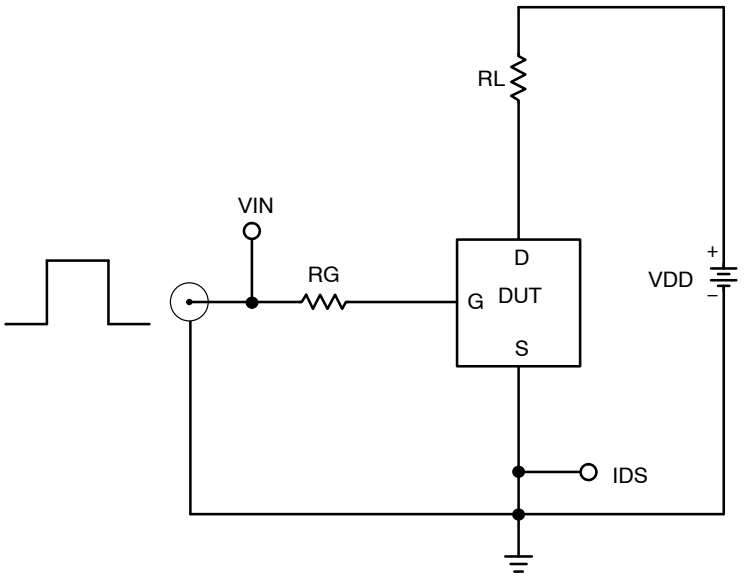


Figure 22. Resistive Load Switching Test Circuit

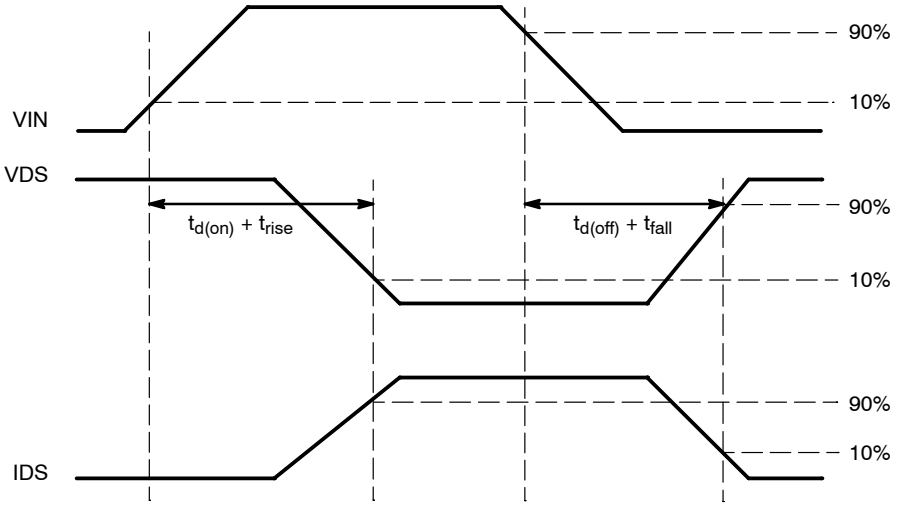


Figure 23. Resistive Load Switching Waveforms

TEST CIRCUITS AND WAVEFORMS

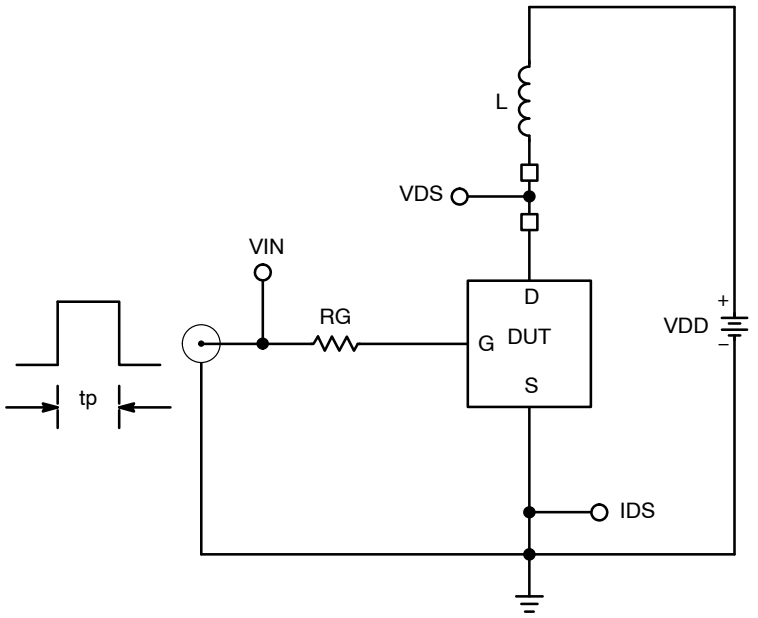


Figure 24. Inductive Load Switching Test Circuit

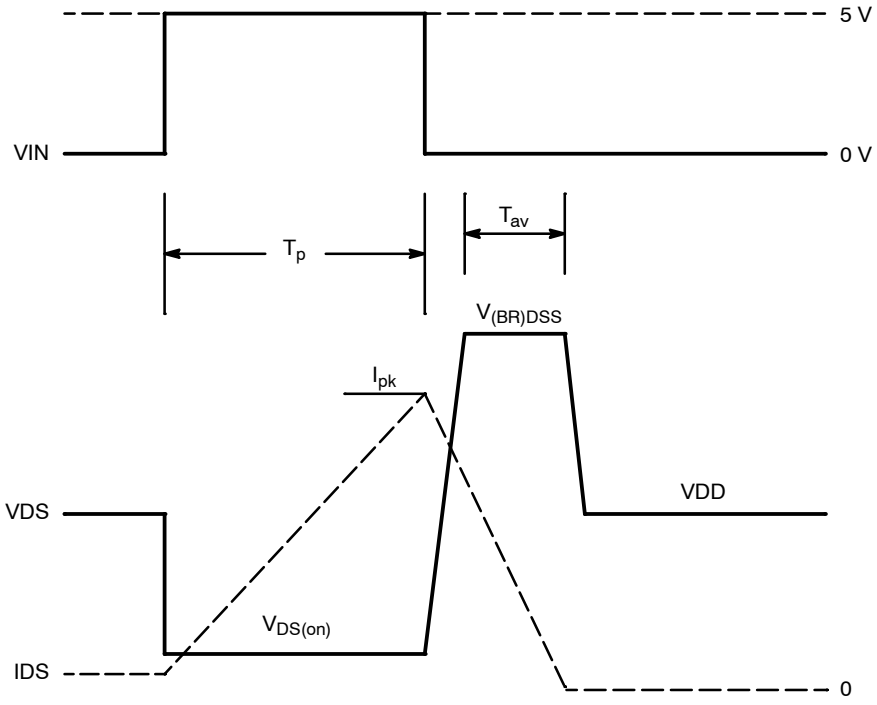


Figure 25. Inductive Load Switching Waveforms

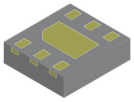
ORDERING INFORMATION

Device*	Package	Shipping†
NCV8402STT1G	SOT−223 (Pb−Free)	1000 / Tape & Reel
NCV8402ASTT1G		
NCV8402STT3G	SOT−223 (Pb−Free)	4000 / Tape & Reel
NCV8402ASTT3G		
NCV8402AMNT2G	DFN6 (Pb−Free)	2000 / Tape & Reel
NCV8402AMNWT1G	DFN6 (Pb−Free, Wettable Flank)	3000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

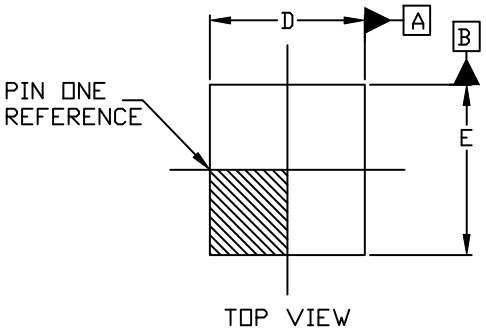
*NCV Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC−Q101 Qualified and PPAP Capable.

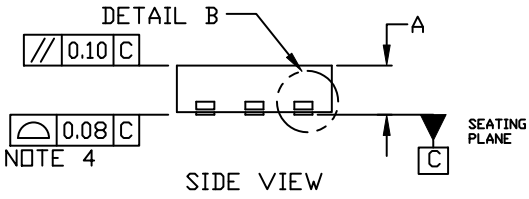
PACKAGE DIMENSIONS

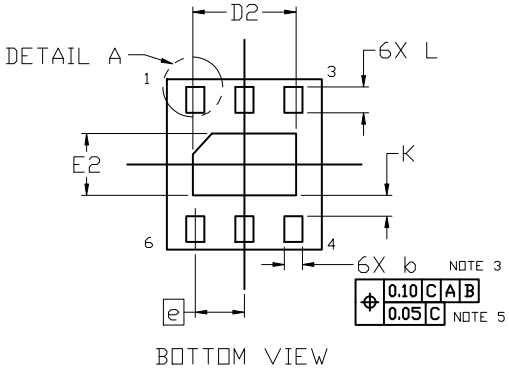


DFN6 3.0x3.3, 0.95P
CASE 506AX
ISSUE A

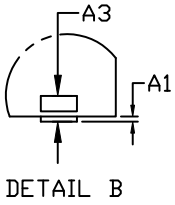
DATE 22 SEP 2020

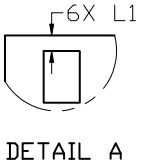




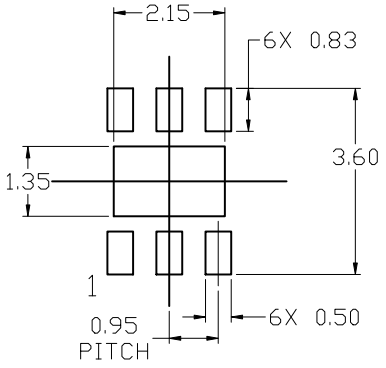


NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
2. CONTROLLING DIMENSION: MILLIMETERS
3. DIMENSION b APPLIES TO PLATED TERMINALS AND IS MEASURED BETWEEN 0.15 AND 0.30MM FROM THE TERMINAL TIP.
4. COPLANARITY APPLIES TO THE EXPOSED PAD AS WELL AS THE TERMINALS.
5. POSITIONAL TOLERANCE APPLIES TO THE EXPOSED PAD AS WELL AS THE TERMINALS.



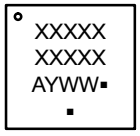


DIM	MILLIMETERS		
	MIN.	NOM.	MAX.
A	0.80	0.90	1.00
A1	0.00	---	0.05
b	0.30	0.35	0.40
D	2.90	3.00	3.10
D2	1.90	2.00	2.10
E	3.20	3.30	3.40
E2	1.10	1.20	1.30
e	0.95 BSC		
K	0.40 REF		
L	0.40	0.50	0.60
L1	0.00	---	0.15



* For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

GENERIC MARKING DIAGRAM*



XXXX = Specific Device Code
A = Assembly Location
Y = Year
WW = Work Week
▪ = Pb−Free Package

(Note: Microdot may be in either location)

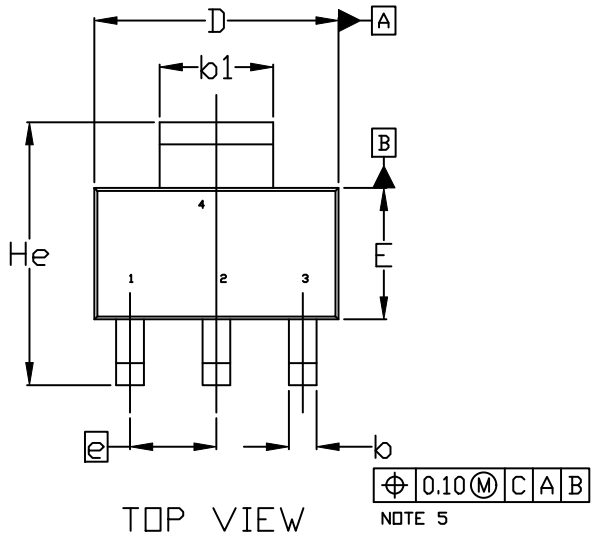
*This information is generic. Please refer to device data sheet for actual part marking. Pb−Free indicator, “G” or microdot “▪”, may or may not be present. Some products may not follow the Generic Marking.

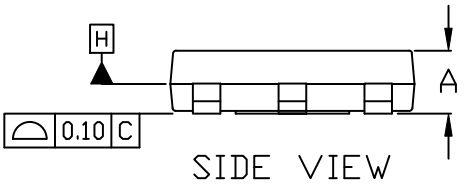
MECHANICAL CASE OUTLINE
PACKAGE DIMENSIONS

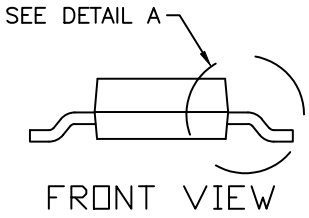
SCALE 1:1

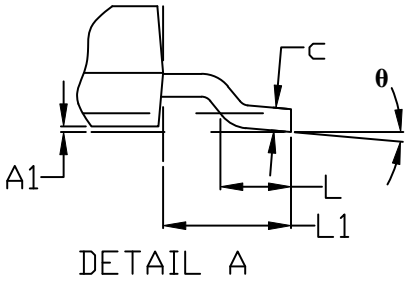
SOT−223 (TO−261)
CASE 318E−04
ISSUE R

DATE 02 OCT 2018



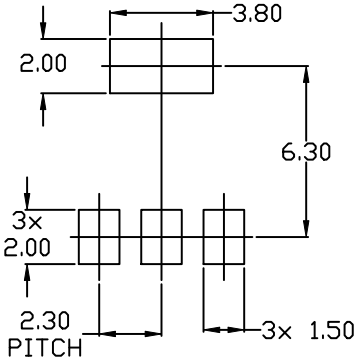






NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. CONTROLLING DIMENSION: MILLIMETERS
3. DIMENSIONS D & E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE BURRS. MOLD FLASH, PROTRUSIONS OR GATE BURRS SHALL NOT EXCEED 0.200MM PER SIDE.
4. DATUMS A AND B ARE DETERMINED AT DATUM H.
5. A1 IS DEFINED AS THE VERTICAL DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT OF THE PACKAGE BODY.
6. POSITIONAL TOLERANCE APPLIES TO DIMENSIONS b AND b1.

	MILLIMETERS		
DIM	MIN.	NOM.	MAX.
A	1.50	1.63	1.75
A1	0.02	0.06	0.10
b	0.60	0.75	0.89
b1	2.90	3.06	3.20
c	0.24	0.29	0.35
D	6.30	6.50	6.70
E	3.30	3.50	3.70
e	2.30 BSC		
L	0.20	---	---
L1	1.50	1.75	2.00
He	6.70	7.00	7.30
θ	0°	---	10°



RECOMMENDED MOUNTING FOOTPRINT

SOT−223 (TO−261)
CASE 318E−04
ISSUE R

DATE 02 OCT 2018

STYLE 1:
PIN 1. BASE
2. COLLECTOR
3. EMITTER
4. COLLECTOR

STYLE 2:
PIN 1. ANODE
2. CATHODE
3. NC
4. CATHODE

STYLE 3:
PIN 1. GATE
2. DRAIN
3. SOURCE
4. DRAIN

STYLE 4:
PIN 1. SOURCE
2. DRAIN
3. GATE
4. DRAIN

STYLE 5:
PIN 1. DRAIN
2. GATE
3. SOURCE
4. GATE

STYLE 6:
PIN 1. RETURN
2. INPUT
3. OUTPUT
4. INPUT

STYLE 7:
PIN 1. ANODE 1
2. CATHODE
3. ANODE 2
4. CATHODE

STYLE 8:
CANCELLED

STYLE 9:
PIN 1. INPUT
2. GROUND
3. LOGIC
4. GROUND

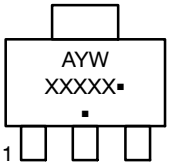
STYLE 10:
PIN 1. CATHODE
2. ANODE
3. GATE
4. ANODE

STYLE 11:
PIN 1. MT 1
2. MT 2
3. GATE
4. MT 2

STYLE 12:
PIN 1. INPUT
2. OUTPUT
3. NC
4. OUTPUT

STYLE 13:
PIN 1. GATE
2. COLLECTOR
3. EMITTER
4. COLLECTOR

GENERIC
MARKING DIAGRAM*



A = Assembly Location
Y = Year
W = Work Week
XXXXX = Specific Device Code
▪ = Pb−Free Package

(Note: Microdot may be in either location)

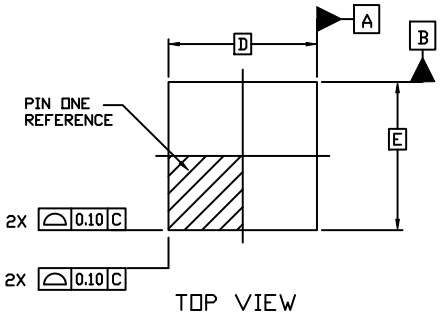
*This information is generic. Please refer to device data sheet for actual part marking. Pb−Free indicator, “G” or microdot “▪”, may or may not be present. Some products may not follow the Generic Marking.

MECHANICAL CASE OUTLINE
PACKAGE DIMENSIONS

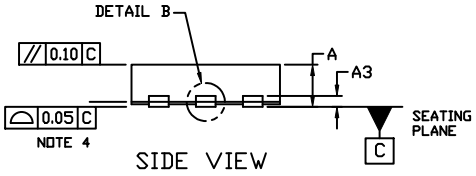
SCALE 2:1

DFNW6 3x3, 0.95P
CASE 506DK
ISSUE A

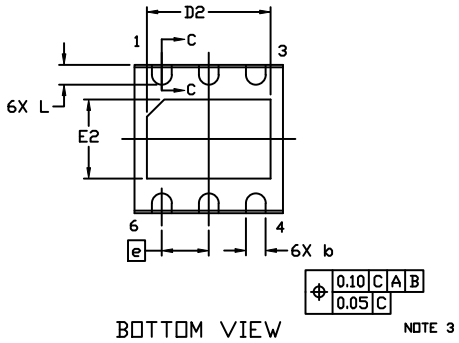
DATE 07 MAY 2021



TOP VIEW



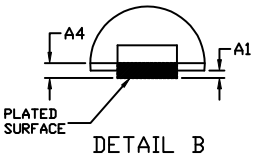
SIDE VIEW



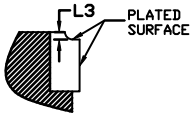
BOTTOM VIEW

NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. CONTROLLING DIMENSION: MILLIMETERS
3. DIMENSION b APPLIES TO THE PLATED TERMINALS AND IS MEASURED BETWEEN 0.10 AND 0.20mm FROM THE TERMINAL TIP.
4. PROFILE APPLIES TO THE EXPOSED PAD AS WELL AS THE TERMINALS.

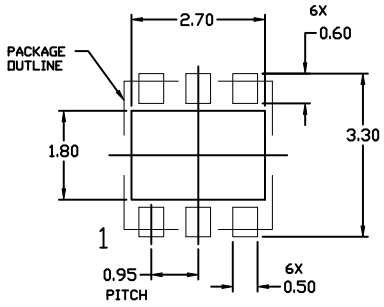


DETAIL B



SECTION C-C

DIM	MILLIMETERS		
	MIN.	MAX.	MAX.
A	0.75	0.85	0.95
A1	0.00	---	0.05
A3	0.20 REF		
A4	0.10	---	---
b	0.35	0.40	0.45
D	3.00 BSC		
D2	2.40	2.50	2.60
E	3.00 BSC		
E2	1.50	1.60	1.70
e	0.95 BSC		
L	0.30	0.40	0.50
L3	0.00	0.05	0.10



RECOMMENDED MOUNTING FOOTPRINT

* For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

GENERIC MARKING DIAGRAM*

XXXXX = Specific Device Code
A = Assembly Location
L = Wafer Lot
Y = Year
W = Work Week
▪ = Pb−Free Package

(Note: Microdot may be in either location)

*This information is generic. Please refer to device data sheet for actual part marking. Pb−Free indicator, “G” or microdot “▪”, may or may not be present. Some products may not follow the Generic Marking.